

HETERO JUNCTION FIELD EFFECT TRANSISTOR

NE1280 SERIES

K-BAND MEDIUM POWER AMPLIFIER

N-CHANNEL HJ-FET CHIPS

DESCRIPTION

The NE1280 series is medium power HJ-FET chips which offer high output power and high gain for telecom transmit power amplifier applications to 30 GHz.

NE1280100 is one cell die of 450 μm gate width, offering 0.1 W output power. NE1280200 is two cells of 900 μm gate width, offering 0.2 W output power.

NE1280400 is four cells of 1.8 μm gate width, offering 0.4 W output power.

The devices incorporate WSi/Au gate to get high gain and silicon nitride glassivation for superior scratch resistance and mechanical protection.

Via hole source grounding result in superior RF performance. To reduce the thermal resistance, the devices have a PHS. (Plated Heat Sink)

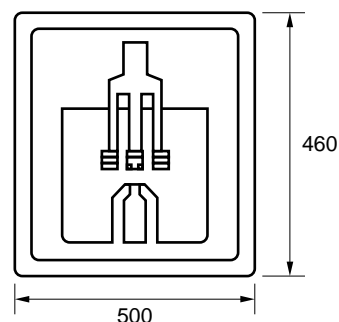
NEC's stringent quality assurance and test procedures assure the highest reliability and performance.

FEATURES

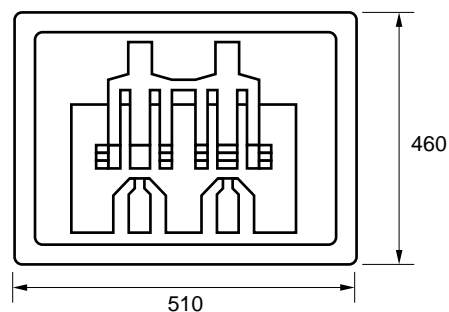
- Class A operation
- High power output
- High linear gain
- High reliability

CHIP DIMENSIONS (unit: μm)

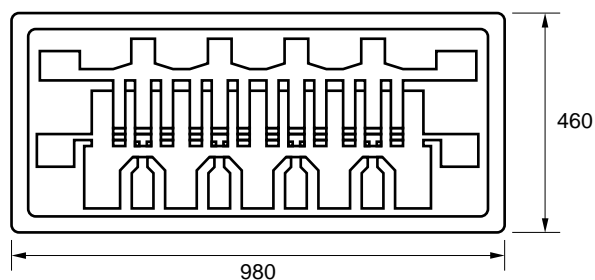
NE1280100



NE1280200



NE1280400



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C)

CHARACTERISTIC	SYMBOL	RATINGS			UNIT
		NE1280100	NE1280200	NE1280400	
Drain to Source Voltage	V _{DS}	10	10	10	V
Gate to Source Voltage	V _{GSO}	-5	-5	-5	V
Total Power Disipation	P _T	1.2	2.5	5.0	W
Drain Current	I _D	0.3	0.6	1.2	A
Gate Current	I _G	1.0	2.0	4.0	mA
Channel Temperature	T _{ch}	175	175	175	°C
Storage Temperature	T _{stg}	-65 to +175	-65 to +175	-65 to +175	°C

RECOMMENDED OPERATION RANGE

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Drain to Source Voltage	V _{DS}	4	-	5	V
Drain Current	I _{DS}	-	0.4*I _{DSs}	0.5*I _{DSs}	mA
Gain Compression	G _{comp}	-	2	3	dBcomp

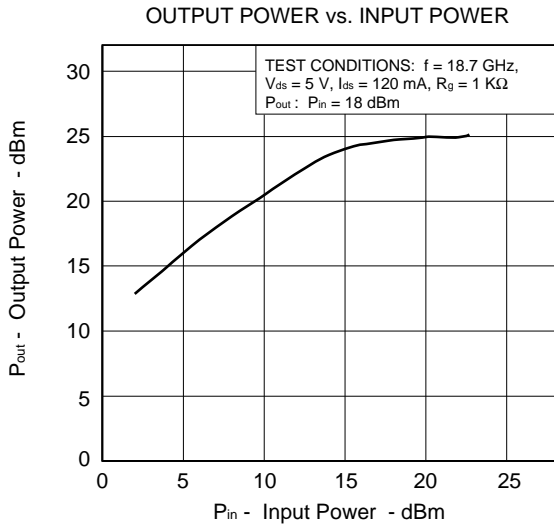
PERFORMANCE SPECIFICATIONS (T_A = 25)

PART NUMBER	P _{out} (dBm)			G _L (dB)			TEST CONDITIONS
	MIN.	TYP.	UNIT	MIN.	TYP.	UNIT	
NE1280100	20.5	21.5	dBm	9.5	10.5	dB	f = 18.7 GHz, V _D = 5 V, I _D = 60 mA R _g = 1 kΩ set, Pin = 14 dBm(*)
NE1280200	23.5	24.5	dBm	8.5	10.0	dB	f = 18.7 GHz, V _D = 5 V, I _D = 120 mA R _g = 1 kΩ set, Pin = 18 dBm(*)
NE1280400	26.5	27.5	dBm	7.5	9.0	dB	f = 18.7 GHz, V _D = 5 V, I _D = 240 mA R _g = 1 kΩ set, Pin = 22 dBm(*)

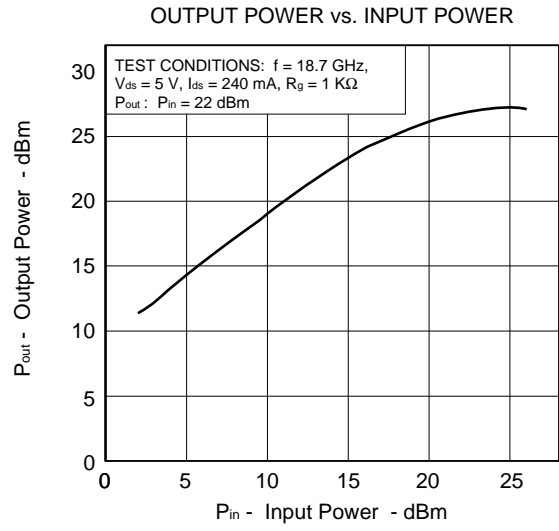
* Pin for P_{out} specification

TYPICAL CHARACTERISTICS (T_A = 25 °C)

NE1280200



NE1280400



S-PARAMETER

NE1280100

FREQUENCY GHz	S11		S21		S12		S22	
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
2.0	0.971	-51.6	8.94	148.0	0.026	62.2	0.524	-20.4
4.0	0.922	-88.3	7.09	125.4	0.040	43.2	0.454	-33.8
6.0	0.902	-113.6	5.43	109.2	0.048	31.4	0.408	-43.0
8.0	0.883	-128.9	4.37	98.1	0.051	23.7	0.384	-49.6
10.0	0.871	-139.2	3.63	89.3	0.052	17.6	0.372	-55.5
12.0	0.862	-147.2	3.03	81.3	0.052	13.0	0.370	-60.7
14.0	0.855	-152.3	2.63	75.1	0.052	10.3	0.375	-65.9
16.0	0.847	-156.6	2.28	68.6	0.049	5.7	0.375	-70.8
18.0	0.862	-159.8	2.06	64.0	0.050	9.7	0.398	-75.3
20.0	0.874	-163.5	1.87	58.2	0.053	7.4	0.410	-79.9

Measured with $V_{DC} = 5\text{ V}$, $I_{DS} = 1/2 I_{DSS}$

NE1280200

FREQUENCY GHz	S11		S21		S12		S22	
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
2.0	0.948	-94.8	10.91	125.9	0.032	40.6	0.248	-76.4
4.0	0.918	-130.9	6.72	103.3	0.038	21.6	0.234	-104.2
6.0	0.917	-147.2	4.57	90.6	0.040	12.9	0.252	-114.7
8.0	0.913	-156.1	3.48	82.3	0.040	7.9	0.278	-119.2
10.0	0.910	-161.1	2.79	75.3	0.040	3.4	0.307	-122.2
12.0	0.907	-164.9	2.31	68.5	0.039	0.2	0.337	-124.0
14.0	0.905	-167.2	1.95	62.9	0.038	-1.9	0.370	-125.7
16.0	0.904	-169.5	1.67	57.1	0.037	-2.7	0.397	-128.2
18.0	0.914	-170.9	1.49	52.6	0.037	-1.7	0.436	-128.8
20.0	0.920	-172.2	1.32	46.9	0.037	-3.8	0.465	-130.6

Calculated from the S-parameter of the NE1280100 with $V_{DC} = 5\text{ V}$, $I_{DS} = 1/2 I_{DSS}$

NE1280400

FREQUENCY GHz	S11		S21		S12		S22	
	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
2.0	0.949	-135.9	8.90	105.3	0.026	20.1	0.407	-156.7
4.0	0.940	-157.2	4.75	89.4	0.027	7.7	0.437	-161.8
6.0	0.944	-165.1	3.09	79.7	0.027	2.1	0.462	-161.2
8.0	0.944	-169.3	2.30	73.1	0.026	-1.3	0.487	-159.9
10.0	0.943	-171.5	1.82	66.7	0.026	-5.1	0.513	-158.8
12.0	0.942	-173.2	1.49	60.4	0.025	-7.8	0.539	-157.9
14.0	0.942	-174.1	1.25	54.9	0.024	-9.9	0.568	-157.3
16.0	0.943	-175.1	1.05	49.4	0.023	-10.4	0.594	-157.5
18.0	0.949	-175.8	0.93	44.7	0.023	-9.6	0.624	-156.9
20.0	0.952	-176.4	0.82	39.1	0.023	-11.6	0.648	-157.1

$V_{DS} = 5\text{ V}$, $I_{DS} = 240\text{ mA}$

CHIP HANDLING**DIE ATTACHMENT**

Die attach can be accomplished with a Au-Sn (300 ± 10 °C) performs in a forming gas environment.
Epoxy die attach is not recommended.

BONDING

Gate and drain bonding wires should be minimum length, semi-hard gold wire (3-8 % elongation) 30 microns or less in diameter.

Bonding should be performed with a wedge tip that has a taper of approximately 15 %.

Die attach and bonding time should be kept to a minimum. As a general rule, the bonding operation should be kept within a 280 °C _ 5 minute curve. If longer periods are required, the temperature should be lowered.

PRECAUTIONS

The user must operate in a clean, dry environment.

The chip channel is glassivated for mechanical protection only and does not preclude the necessity of a clean environment.

The bonding equipment should be periodically checked for sources of surge voltage and should be properly grounded at all times. In fact, all test and handling equipment should be grounded to minimize the possibilities of static discharge.

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Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)

Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

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Anti-radioactive design is not implemented in this product.